

Amdt. dated December 22, 2003

Reply to Office action of August 27, 2003

**Amendments to the Specification:**

**In the Summary of the Invention:**

*Please replace the paragraph beginning on page 5, line 28, with the following marked-up paragraph using strikethrough for deletions and underlining for additions:*

The monitoring system of the present invention is used for monitoring alignment of a spindle trunnion axis of a computer numerically controlled (CNC) machine and includes the fixture and a probe to measure locations of features including the probe blocks on the fixture. The probe is mounted in a tool holder mounted on ~~of~~ a spindle of the machine and a CNC controller is used for moving and operating the spindle mounted probe. Means are provided for ~~and~~ measuring, recording, and displaying location data probed by the probe against the flat surfaces. The means is effective to display the location data as a deviation from baseline measurements.

**In the Detailed Description:**

*Please replace the paragraph beginning on page 13, line 25, with the following marked-up paragraph using brackets for deletions and underlining for additions:*

1. The spindle mounted probe 66 is positioned on “left” side of the fixture 50. The trunnion axis A is offset in the Z and Y direction from the axis of rotation 114. The probe 66 is rotated about the trunnion axis A, along [[a]] an arched path 150 as illustrated in FIG. 13, and is moved in the X direction above the first probe block 94. Then the probe 66 is translated along a straight path 152 in the [[-]] ± Y direction to hit a first Y touch point 140 on the second surface 84 on the first probe block 94. A first value of a Y-axis hit location Y12 is recorded.

*Please replace the paragraph beginning on page 14, line 5, with the following marked-up paragraph using brackets for deletions and underlining for additions:*

2. The trunnion axis A is offset in the Z and Y direction from the axis of rotation 114. The probe 66 is rotated about the trunnion axis A, along [[a]] an arched path 150 as illustrated in FIG. 13, and is

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moved in the X direction above the second surface 84 on the second probe block 96. Then the probe 66 is then translated along a straight path 152 in the  $[[\cdot]] \pm Y$  direction to hit a second Y touch point 142 on the second surface 84 on the second probe block 96. This second value of a Y-axis hit location Y13 is recorded.

*Please replace the paragraph beginning on page 14, line 16, with the following marked-up paragraph using brackets for deletions and underlining for additions:*

3. The probe 66 is rotated about the A-axis and is moved in the X direction above the second surface 84 of the third probe block 98. Then the probe 66 is then translated along a straight path 152 in the  $[[\cdot]] \pm Y$  direction to hit a third Y touch point 144 on the second surface 84 on the third probe block 98. This third value of a Y-axis hit location Y14 is recorded.